



PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

August 9, 2004

Applicant(s): Robin James SPIVEY et al.

For: SCREENING DEVICE AND METHODS OF SCREENING  
IMMUNOASSAY TESTS AND AGGLUTINATION TESTS

Serial No.: 09/760 374 Group: 1641

Confirmation No.: 1252

Filed: January 12, 2001 Examiner: K. Padmanabhan

Atty. Docket No.: R&G C-317

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(c)(2) and 1.98, listed on Form PTO-1449 are references for the Examiner's consideration.

Copies of cited U.S. patents are not submitted in accordance with the USPTO waiver of the requirement under 37 CFR 1.98(a)(2)(i) [1273 Off. Gaz. Pat. Off. 8/5/2003]. Copies of all other references listed on Form PTO-1449 are enclosed.

An attached check includes the requisite fee of \$180.00 under 37 CFR 1.17(p). The Commissioner is hereby authorized to charge any additional fees which may be required by this paper, or to credit any overpayment, to Deposit Account No. 06-1382. A duplicate copy of this sheet is enclosed.

Applicants respectfully request confirmation that the reference identified on Form PTO-1449 has been considered herein.

Respectfully submitted,

IN DUPLICATE

08/12/2004 ZJUHAR1 00000032 09760374

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180.00 DP

Dale H. Thiel

DHT/jp

FLYNN, THIEL, BOUTELL & TANIS, P.C. 2026 Rambling Road Kalamazoo, MI 49008-1631 Phone: (269) 381-1156 Fax: (269) 381-5465	Dale H. Thiel David G. Boutell Ronald J. Tanis Terryence F. Chapman Mark L. Maki Liane L. Churney Brian R. Tumm Steven R. Thiel Sidney B. Williams, Jr.	Reg. No. 24 323 Reg. No. 25 072 Reg. No. 22 724 Reg. No. 32 549 Reg. No. 36 589 Reg. No. 40 694 Reg. No. 36 328 Reg. No. 53 685 Reg. No. 24 949
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Encl: Form PTO-1449 and copy of listed foreign reference

110.0703

INFORMATION DISCLOSURE CITATION	Applicant: Robin James SPIVEY et al. Ser.No. : 09/760 374 Filed : January 12, 2001 Conf. No.: 1252 Atty.Ref.: R&G C-317 Group : 1641
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## U.S. PATENT DOCUMENTS

Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date
	AA	5 393 496	02/1995	Seymour			
<i>1 P E JCIS</i> AUG 12 2004 PATENT & TRADEMARK OFFICE	AB	5 408 535	04/1995	Howard, III et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation Yes No
	AL	WO 98/32004	07/1998	WIPO	English language reference		
	AM						
	AN						
	AO						
	AP						

## OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

AR	
AS	

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.